Measurement of Dielectric Properties under SPACE Conditions



STP 420 AMERICAN SOCIETY for TESTING and MATERIALS

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A symposium presented at the Sixty-ninth Annual Meeting AMERICAN SOCIETY FOR TESTING AND MATERIALS Atlantic City, N.J., 26 June–1 July, 1966

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Foreword

The Symposium on Measurement of Dielectric Properties Under Space Conditions was presented in two sessions during the 69th Annual Meeting of the Society, in Atlantic City, N.J., 26 June-1 July, 1966. The symposium was sponsored by Committee D-9 on Electrical Insulating Materials. The symposium chairman was R. B. Feuchtbaum, Hughes Aircraft Co. Presiding at the two sessions were K. N. Mathes, General Electric Co., and W. G. Long, Atomics International, Division of North American Aviation.

Related ASTM Publications

Factors in the Operation of Manned Space Chambers, STP 398 (1966), \$8.00

Radiation Effects in Electronics, STP 384 (1965), \$5.00

Newer Structural Materials for Aerospace Vehicles, STP 379 (1965), \$6.00

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